## CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service on the date shown below with sufficient postage as first class mail in an envelope addressed to the: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 3 v ~ \4\4\2007



IFW

PATENT ESD1.PAU.01

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Rodov et al.

Serial No.:

10/635,391

Filed:

August 6, 2003

Title:

Method and Apparatus for

**Preventing Microcircuit** 

Thermo-Mechanical Damage

**During and ESD Event** 

Art Unit:

2811

Examiner:

Unknown

**INFORMATION DISCLOSURE STATEMENT** 

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. § 1.56, Applicant(s) submit herewith the attached Information Disclosure Statement Form PTO-1449 in connection with the above-identified patent application. The statement is not a representation that all of the information cited is necessarily effective as prior art against the application. Also, Applicant has co-pending application serial no. 10/635,390 filed August 6, 2003 which may be considered to be directed to related subject matter. If any fee is required for consideration of this Information Disclosure Statement please charge Deposit Account No. 01-1960.

Respectfully submitted,

Data:

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FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. ESD1.PAU.01	SERIAL NO. : 10/635,391
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT  (USE SEVERAL SHEETS IF NECESSARY)	APPLICADA (S): 1 Roder et al.	
(USE SEVERAL SHEETS IF NECESSART)	FILING DATE, August 6, 2003	GROUP: 2811

Reference Designation

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Examiner					Filing Date Subclass if		
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EXAMINER			DATE CONSIDERED				
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